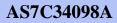
August 2004





$3.3~V~256~K\times 16~CMOS~SRAM$

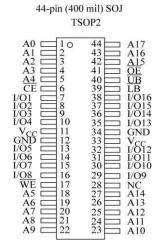
Features

- Pin compatible with AS7C34098
- Industrial and commercial temperature
- Organization: 262,144 words \times 16 bits
- Center power and ground pins
- High speed
 - 10/12/15/20 ns address access time
 - 4/5/6/7 ns output enable access time
- Low power consumption: ACTIVE - 650 mW /max @ 10 ns
- Low power consumption: STANDBY - 28.8 mW /max CMOS
- Individual byte read/write controls

Logic block diagram

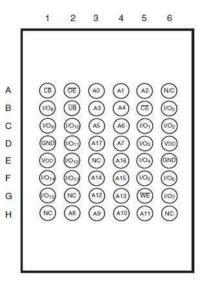
- Easy memory expansion with \overline{CE} , \overline{OE} inputs
- TTL- and CMOS-compatible, three-state I/O
- JEDEC standard packages
- 44-pin SOJ -400-mil
- 44-pin TSOP 2
- 48-pin Mini BGA
- ESD protection ≥ 2000 volts
- Latch-up current $\ge 200 \text{ mA}$

$A0 \rightarrow V_{CC}$ $A2 \rightarrow V_{CC}$ $A3 \rightarrow O$ $A4 \rightarrow O$ $A7 \rightarrow O$ $A7 \rightarrow O$ $A12 \rightarrow O$ $A12 \rightarrow O$ $A12 \rightarrow O$ $A12 \rightarrow O$ $A13 \rightarrow O$ $A12 \rightarrow O$ $A12 \rightarrow O$ $A13 \rightarrow O$ $A12 \rightarrow O$ A12



Pin arrangement for SOJ

and TSOP 2



Bottom View 48BGA

Selection guide

WE

 \overline{UB} \overline{OE}

LB-

CF

		-10	-12	-15	-20	Unit
Maximum address access time		10	12	15	20	ns
Maximum output enable access time		4	5	6	7	ns
Maximum operating current	Industrial	180	160	140	110	mA
	Commercial	170	150	130	100	mA
Maximum CMOS standby current		8	8	8	8	mA

Functional description

The AS7C34098A is a high-performance CMOS 4,194,304-bit Static Random Access Memory (SRAM) device organized as 262,144 words \times 16 bits. It is designed for memory applications where fast data access, low power, and simple interfacing are desired.

Equal address access and cycle times (t_{AA} , t_{RC} , t_{WC}) of 10/12/15/20 ns with output enable access times (t_{OE}) of 4/5/6/7 ns are ideal for high-performance applications. The chip enable input \overline{CE} permits easy memory expansion with multiple-bank memory systems.

When \overline{CE} is high the device enters standby mode. The device is guaranteed not to exceed 28.8mW power consumption in CMOS standby mode. A write cycle is accomplished by asserting write enable (\overline{WE}) and chip enable (\overline{CE}). Data on the input pins I/O1–I/O16 is written on the rising edge of \overline{WE} (write cycle 1) or \overline{CE} (write cycle 2). To avoid bus contention, external devices should drive I/O pins only after outputs have been disabled with output enable (\overline{OE}) or write enable (\overline{WE}).

A read cycle is accomplished by asserting output enable (\overline{OE}) and chip enable (\overline{CE}), with write enable (\overline{WE}) high. The chip drives I/O pins with the data word referenced by the input address. When either chip enable or output enable is inactive, or write enable is active, output drivers stay in high-impedance mode.

The device provides multiple center power and ground pins, and separate byte enable controls, allowing individual bytes to be written and read. \overline{LB} controls the lower bits, I/O1–I/O8, and \overline{UB} controls the higher bits, I/O9–I/O16.

All chip inputs and outputs are TTL- and CMOS-compatible, and operation is for 3.3V (AS7C34098A) supply. The device is available in the JEDEC standard 400-mil, 44-pin SOJ, TSOP 2.

Parameter	Symbol	Min	Max	Unit
Voltage on V _{CC} relative to GND	V _{t1}	-0.50	+5.0	V
Voltage on any pin relative to GND	V _{t2}	-0.50	V _{CC} +0.50	V
Power dissipation	P _D	-	1.5	W
Storage temperature (plastic)	T _{stg}	-65	+150	°C
Ambient temperature with V_{CC} applied	T _{bias}	-55	+125	°C
DC current into outputs (low)	I _{OUT}	_	±20	mA

Absolute maximum ratings

Note: Stresses greater than those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions outside those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

T		401	61	
11	uth	ιa	D.	te

CE	WE	OE	LB	UB	I/O1–I/O8	I/O9–I/O16	Mode
Н	Х	Х	Х	Х	High Z	High Z	Standby (I_{SB}, I_{SB1})
L	Н	Н	Х	Х	Histo 7	III. h 7	Output disable (I _{CC})
L	Х	Х	Н	Н	High Z	High Z	Output disable (I _{CC})
			L	Н	D _{OUT}	High Z	
L	Н	L	Н	L	High Z	D _{OUT}	Read (I _{CC})
			L	L	D _{OUT}	D _{OUT}	
			L	Н	D _{IN}	High Z	
L	L	Х	Н	L	High Z	D _{IN}	
			L	L	D _{IN}	D _{IN}	Write (I _{CC})

Key: X = Don't care, L = Low, H = High.



Recommended operating conditions

Parameter	Parameter		Min	Typical	Max	Unit
Supply voltage	Supply voltage			3.3	3.6	V
Input voltage	Input voltage			_	$V_{CC} + 0.5$	V
input voltage		V _{IL} *	-0.5	_	0.8	V
Ambient operating temperature	commercial	T _A	0	_	70	°C
Amolent operating temperature	industrial	T _A	-40	-	85	°C

 $\label{eq:VIL} \begin{array}{l} * \\ * \\ V_{IL} \\ max = V_{CC} \\ + \\ 2.0V \\ \mbox{for pulse width less than 5ns.} \end{array}$

DC operating characteristics (over the operating range)¹

				-]	10	_	12	-15		-20		
Parameter	Symbol	Test conditions		Min	Max	Min	Max	Min	Max	Min	Max	Unit
Input leakage current	I _{LI}	V _{CC} = Max V _{IN} = GND to V _C	CC	_	1	_	1	_	1	_	1	μA
Output leakage current	I _{LO}	$\frac{V_{CC} = Max}{CE = V_{IH} \text{ or } OE = V_{IH}}$ or $\overline{WE} = V_{IL}$ $V_{I/O} = GND \text{ to } V_{CC}$		_	1	_	1	_	1	_	1	μA
Operating	T	V _{CC} = Max	Industrial	_	180	-	160	—	140	-	110	mA
power supply current	I _{CC}	$\overline{\text{CE}} \le \text{V}_{\text{IL}}, \text{ f} = \text{f}_{\text{max}} \text{I}_{\text{OUT}} = 0 \text{mA}$	Commercial	-	170	-	150	-	130	-	100	mA
Stor dhe sources	I _{SB}	$\frac{V_{CC} = Max}{\overline{CE} \ge V_{IH}, f = Ma}$	IX	_	60	_	60	_	60	_	60	mA
Standby power supply current	I _{SB1}	$\label{eq:VCC} \begin{split} V_{CC} &= Max\\ \overline{CE} \geq V_{CC} - 0.2V, \ V_{IN} \geq V_{CC} - 0.2V \ or\\ V_{IN} \leq 0.2V, \ f = 0 \end{split}$		_	8	_	8	_	8	_	8	mA
Output voltage	V _{OL}	$I_{OL} = 8 \text{ mA}, V_{CC} = Min$		—	0.4	—	0.4	—	0.4	Ι	0.4	V
Sulput totage	V _{OH}	$I_{OH} = -4 \text{ mA}, V_{CC} =$	Min	2.4	-	2.4	—	2.4	-	2.4	-	V

Capacitance (f = 1MHz, $T_a = 25^{\circ} \text{ C}, V_{CC} = \text{NOMINAL})^2$

Parameter	Symbol	Signals	Test conditions	Max	Unit
Input capacitance	C _{IN}	A, CE, WE, OE, UB, LB	$V_{IN} = 0V$	6	pF
I/O capacitance	C _{I/O}	I/O	$V_{IN} = V_{OUT} = 0V$	8	pF

@_

Read cycle (over the operating range)^{3,9}

		-1	10	-1	12	-1	15	-2	20		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Min	Max	Unit	Notes
Read cycle time	t _{RC}	10	-	12	-	15	-	20	-	ns	
Address access time	t _{AA}	-	10	_	12	_	15	_	20	ns	
Chip enable (\overline{CE}) access time	t _{ACE}	-	10	_	12	_	15	-	20	ns	
Output enable (\overline{OE}) access time	t _{OE}	-	4	_	5	_	6	_	7	ns	
Output hold from address change	t _{OH}	3	_	3	_	3	_	3	_	ns	5
$\overline{\operatorname{CE}}$ Low to output in low Z	t _{CLZ}	3	-	3	-	3	_	3	_	ns	4, 5
$\overline{\text{CE}}$ High to output in high Z	t _{CHZ}	_	5	_	6	_	7	_	9	ns	4, 5
OE Low to output in low Z	t _{OLZ}	0	_	0	_	0	_	0	_	ns	4, 5
$\overline{\text{OE}}$ High to output in high Z	t _{OHZ}	-	5	_	6	_	7	_	9	ns	4, 5
$\overline{\text{LB}}, \overline{\text{UB}}$ access time	t _{BA}	-	5	_	6	_	7	_	8	ns	
$\overline{\text{LB}}$, $\overline{\text{UB}}$ Low to output in low Z	t _{BLZ}	0	_	0	_	0	_	0	_	ns	
$\overline{\text{LB}}, \overline{\text{UB}}$ High to output in high Z	t _{BHZ}	_	5	_	6	_	7	-	9	ns	
Power up time	t _{PU}	0	_	0	_	0	_	0	_	ns	5
Power down time	t _{PD}	-	10	—	12	-	15		20	ns	5

Key to switching waveforms

Rising input

Falling input

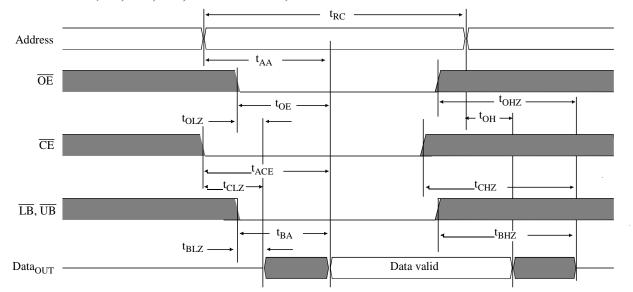
Undefined/don't care

Read waveform 1 (address controlled)^{6,7,9}

		t	RC	
Address				
	$t_{OH} \longrightarrow$	$\xrightarrow{t_{AA}} $		ι←−− t _{OH}
Data _{OUT}	Previous data valid		Data valid	



Read waveform 2 (\overline{CE} , \overline{OE} , \overline{UB} , \overline{LB} controlled)^{6,8,9}



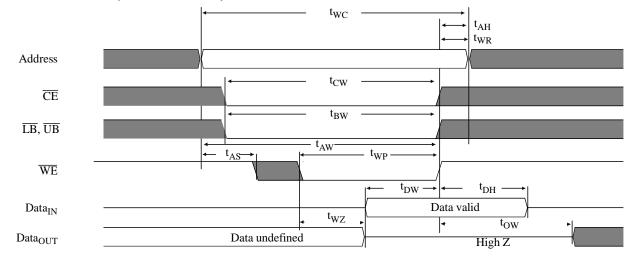
Write cycle (over the operating range)¹⁰

		_	10	_	12	_	15	_	20		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Min	Max	Unit	Note
Write cycle time	t _{WC}	10	-	12	_	15	_	20	_	ns	
Chip enable $\overline{(CE)}$ to write end	t _{CW}	7	_	8	_	10	_	12	_	ns	
Address setup to write end	t _{AW}	7	_	8	_	10	_	12	_	ns	
Address setup time	t _{AS}	0	_	0	_	0	_	0	_	ns	
Write pulse width ($\overline{OE} = High$)	t _{WP1}	7	_	8	_	10	_	12	_	ns	
Write pulse width ($\overline{OE} = Low$)	t _{WP2}	10	_	12	_	15	_	20	_	ns	
Write recovery time	t _{WR}	0	_	0	_	0	_	0	_	ns	
Address hold from end of write	t _{AH}	0	_	0	_	0	_	0	_	ns	
Data valid to write end	t _{DW}	5	_	6		7		9		ns	
Data hold time	t _{DH}	0	_	0	_	0	_	0	_	ns	4, 5
Write enable to output in High-Z	t _{WZ}	0	5	0	6	0	7	0	9	ns	4, 5
Output active from write end	t _{OW}	3	-	3	-	3	-	3	-	ns	4, 5
Byte enable Low to write end	t _{BW}	7	_	8	_	10	_	12	_	ns	4, 5

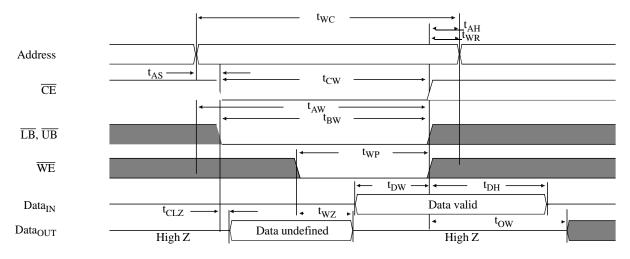
AS7C34098A



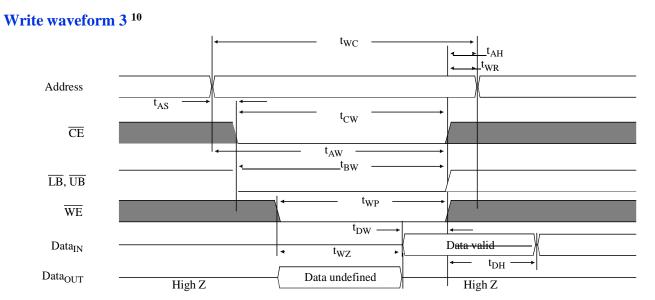
Write waveform $1(\overline{WE} \text{ controlled})^{10}$



Write waveform 2 (CE controlled)¹⁰

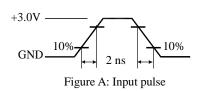


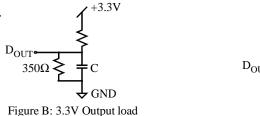




AC test conditions

- Output load: see Figure B.
- Input pulse level: GND to 3.0V. See Figure A.
- Input rise and fall times: 2 ns. See Figure A.
- Input and output timing reference levels: 1.5V.



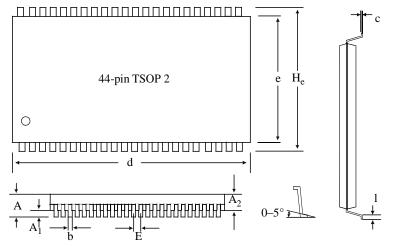




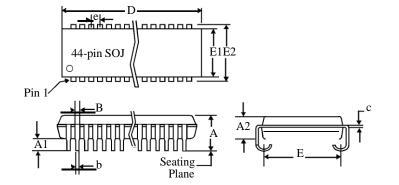
Notes

- 1 During V_{CC} power-up, a pull-up resistor to V_{CC} on \overline{CE} is required to meet I_{SB} specification.
- 2 This parameter is sampled, but not 100% tested.
- 3 For test conditions, see AC Test Conditions, Figures A and B.
- 4 t_{CLZ} and t_{CHZ} are specified with $C_L = 5pF$ as in Figure B. Transition is measured $\pm 500mV$ from steady-state voltage.
- 5 This parameter is guaranteed, but not tested.
- $\overline{\text{WE}}$ is High for read cycle.
- 7 $\overline{\text{CE}}$ and $\overline{\text{OE}}$ are Low for read cycle.
- 8 Address valid prior to or coincident with $\overline{\text{CE}}$ transition Low.
- 9 All read cycle timings are referenced from the last valid address to the first transitioning address.
- 10 All write cycle timings are referenced from the last valid address to the first transitioning address.
- 11 C=30pF, except on High Z and Low Z parameters, where C=5pF.

Package dimensions



	44-pin '	TSOP 2
	Min (mm)	Max (mm)
A		1.2
A ₁	0.05	0.15
A ₂	0.95	1.05
b	0.3	0.45
С	0.12	0.21
d	18.31	18.52
е	10.06	10.26
H _e	11.68	11.94
E	0.80 (t	ypical)
l	0.40	0.60

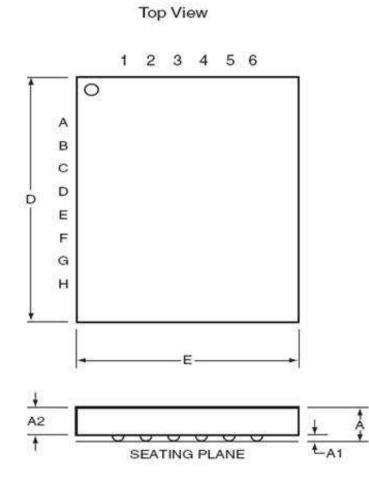


	44-pin SO	J 400 mils
	Min(mils)	Max(mils)
Α	0.128	0.148
A1	0.025	-
A2	0.105	0.115
B	0.026	0.032
b	0.015	0.020
С	0.007	0.013
D	1.120	1.130
E	0.370	NOM
E1	0.395	0.405
E2	0.435	0.445
e	0.050	NOM

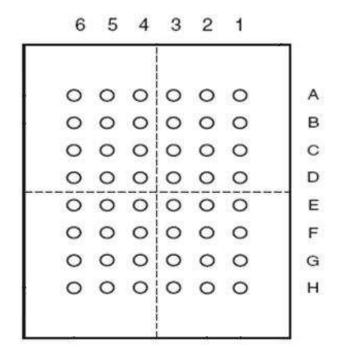
AS7C34098A



Outline of 48BGA



Bottom View





1. Controlling dimensions are in millimeters.



	MILLIMETERS				
Sym.	Min.	Тур.	Max.		
A	332	<u></u>	1.20		
A1	0.24	<u>2-3</u> 1	0.30		
A2	0.60		94-23		
D	9.90	10.00	10.10		
D1	5.25 BSC				
E	7.90	8.00	8.10		
E1	3	.75 BS	С		
е	0	.75 BS	С		
b	0.30	0.35	0.40		



Ordering Codes

Package	Temperature	10 ns	12	15 ns	20 ns
SOJ	Commercial	AS7C34098A-10JC	AS7C34098A-12JC	AS7C34098A-15JC	AS7C34098A-20JC
	Industrial	AS7C34098A-10JI	AS7C34098A-12JI	AS7C34098A-15JI	AS7C34098A-20JI
BGA	Industrial	AS7C34098A-10BIN			
TSOP 2	Commercial	AS7C34098A-10TC	AS7C34098A-12TC	AS7C34098A-15TC	AS7C34098A-20TC
	Industrial	AS7C34098A-10TI	AS7C34098A-12TI	AS7C34098A-15TI	AS7C34098A-20TI

Note: Add suffix 'N' to the above part numbers for Lead Free Parts. (EX: AS7C34098A - 10TCN)

Part numbering system

AS7C	X	4098A	-XX	J / T or B	X	X
SRAM prefix	Voltage: 3 - 3.3V CMOS	Device number	Access time	Packages: J: SOJ 400 mil T: TSOP 2 B: BGA	Temperature ranges: C: Commercial, 0°C to 70°C I: Industrial, –40°C to 85°C	



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